

Notice of References Cited

Application/Control No.

09/577,551

Applicant(s)/Patent Under

Reexamination

DUNSHEE ET AL.

Examiner

Patrick D. Niland

Art Unit

1714

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
A	US-5162141	11-1992	Davey et al.	--	--
B	US-4334530	06-1982	Hassell	--	--
C	US-				
D	US-				
E	US-				
F	US-				
G	US-				
H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
N	EP 596503	05-1994	EP	Miyamoto et al.	--	--
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S						
T						

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U		
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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